

PALM INTRANET

Day: Tuesday
Date: 5/6/2008
Time: 17:57:00

Inventor Name Search Result

Your Search was:

Last Name = HONDA

First Name = TOSHIFUMI

Application#	Patent#	Status	Date Filed	Title	Inventor Name
08967015	6333992 ✓	150	11/10/1997	DEFECT JUDGEMENT PROCESSING METHOD AND APPARATUS	HONDA, TOSHIFUMI
08968125	6249598	150	11/12/1997	SOLDER TESTING APPARATUS	HONDA, TOSHIFUMI
09413468	6622054 ✓	150	10/06/1999	METHOD MONITORING A QUALITY OF ELECTRONIC CIRCUITS AND ITS MANUFACTURING CONDITION AND SYSTEM FOR IT	HONDA, TOSHIFUMI
09661182	6553323 ✓	150	09/13/2000	METHOD AND ITS APPARATUS FOR INSPECTING A SPECIMEN	HONDA, TOSHIFUMI
10081782	7181060 ✓	150	02/20/2002	DEFECT INSPECTION METHOD	HONDA, TOSHIFUMI
10224087	6965429 ✓	150	08/19/2002	METHOD OF REVIEWING DETECTED DEFECTS	HONDA, TOSHIFUMI
10256585	6855930 ✓	150	09/27/2002	DEFECT INSPECTION APPARATUS AND DEFECT INSPECTION METHOD	HONDA, TOSHIFUMI
10378016 ✓	Not Issued	71	02/28/2003	Method and its apparatus for classifying defects	HONDA, TOSHIFUMI
10640343 ✓	Not Issued	71	08/12/2003	Defect inspection method	HONDA, TOSHIFUMI
10762091 ✓	Not Issued	71	01/20/2004	Method of classifying defects	HONDA, TOSHIFUMI
10794267 ✓	Not Issued	41	03/04/2004	Defect classification method	HONDA, TOSHIFUMI
10809464 ✓	Not Issued	61	03/26/2004	Method and its apparatus for classifying defects	HONDA, TOSHIFUMI
10954421 ✓	Not Issued	71	10/01/2004	Method of observing defects	HONDA, TOSHIFUMI

11020255	7105815 ✓	150	12/27/2004	METHOD AND APPARATUS FOR COLLECTING DEFECT IMAGES	HONDA, TOSHIFUMI
11020265	7075077 ✓	150	12/27/2004	METHOD OF OBSERVING A SPECIMEN USING A SCANNING ELECTRON MICROSCOPE	HONDA, TOSHIFUMI
11042021	7205555 ✓	150	01/24/2005	DEFECT INSPECTION APPARATUS AND DEFECT INSPECTION METHOD	HONDA, TOSHIFUMI
11130121	7361896	150	05/17/2005	SCANNING ELECTRON MICROSCOPE AND A METHOD FOR ADJUSTING A FOCAL POINT OF AN ELECTRON BEAM OF SAID SCANNING ELECTRON MICROSCOPE	HONDA, TOSHIFUMI
11190829 ✓	Not Issued	30	07/28/2005	Method and its apparatus for classifying defects	HONDA, TOSHIFUMI
11248697	7170593 ✓	150	10/11/2005	METHOD OF REVIEWING DETECTED DEFECTS	HONDA, TOSHIFUMI
11268568 ✓	Not Issued	41	11/08/2005	Scanning electron microscope and system for inspecting semiconductor device	HONDA, TOSHIFUMI
11311254 ✓	Not Issued	30	12/20/2005	Method and apparatus for reviewing defects	HONDA, TOSHIFUMI
11319721	Not Issued	71	12/29/2005	Scanning electron microscope and method for detecting an image using the same	HONDA, TOSHIFUMI
11325582 ✓	Not Issued	30	01/05/2006	Method and apparatus for reviewing defects	HONDA, TOSHIFUMI
11415286	Not Issued	30	05/02/2006	Observing method and its apparatus using electron microscope	HONDA, TOSHIFUMI
11488636 ✓	Not Issued	30	07/19/2006	Method and apparatus for reviewing defects of semiconductor device	HONDA, TOSHIFUMI
11634963 ✓	Not Issued	30	12/07/2006	Method and apparatus of reviewing defects on a semiconductor device	HONDA, TOSHIFUMI
11668510 ✓	Not Issued	30	01/30/2007	METHOD AND APPARATUS FOR REVIEWING DEFECTS	HONDA, TOSHIFUMI
11677669 ✓	Not Issued	30	02/22/2007	METHOD AND APPARATUS FOR DISPLAYING DETECTED DEFECTS	HONDA, TOSHIFUMI

11704228 ✓	Not Issued	51	02/09/2007	Method and apparatus for reviewing defects by detecting images having voltage contrast	HONDA, TOSHIFUMI
11704350 ✓	Not Issued	30	02/09/2007	Method and apparatus for reviewing defects	HONDA, TOSHIFUMI
11747253 ✓	Not Issued	25	05/11/2007	SEM-TYPE REVIEWING APPARATUS AND A METHOD FOR REVIEWING DEFECTS USING THE SAME	HONDA, TOSHIFUMI
11779937 ✓	Not Issued	30	07/19/2007	REVIEWING APPARATUS USING A SEM AND METHOD FOR REVIEWING DEFECTS OR DETECTING DEFECTS USING THE REVIEWING APPARATUS	HONDA, TOSHIFUMI
12033470 ✓	Not Issued	19	01/01/0001	DEFECT REVIEW METHOD AND DEVICE FOR SEMICONDUCTOR DEVICE	HONDA, TOSHIFUMI

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Inventor Name Search Result

Your Search was:

Last Name = OKUDA

First Name = HIROHITO

Application#	Patents	Status	Date Filed	Title	Inventor Name
09413468	6622054	150	10/06/1999	METHOD MONITORING A QUALITY OF ELECTRONIC CIRCUITS AND ITS MANUFACTURING CONDITION AND SYSTEM FOR IT	OKUDA, HIROHITO
10650519	7231079 ✓	150	01/18/2002	METHOD AND SYSTEM FOR INSPECTING ELECTRONIC CIRCUIT PATTERN	OKUDA, HIROHITO
10681782	7181060 ✓	150	02/20/2002	DEFECT INSPECTION METHOD	OKUDA, HIROHITO
10224087	6965429 ✓	150	08/19/2002	METHOD OF REVIEWING DETECTED DEFECTS	OKUDA, HIROHITO
10256585	6855930 ✓	150	09/27/2002	DEFECT INSPECTION APPARATUS AND DEFECT INSPECTION METHOD	OKUDA, HIROHITO
10378016 ✓	Not Issued	71	02/28/2003	Method and its apparatus for classifying defects	OKUDA, HIROHITO
10640343 ✓	Not Issued	71	08/12/2003	Defect inspection method	OKUDA, HIROHITO
10762091 ✓	Not Issued	71	01/20/2004	Method of classifying defects	OKUDA, HIROHITO
10794267 ✓	Not Issued	41	03/04/2004	Defect classification method	OKUDA, HIROHITO
10809464 ✓	Not Issued	61	03/26/2004	Method and its apparatus for classifying defects	OKUDA, HIROHITO
10918340	7034299	150	08/16/2004	TRANSMISSION ELECTRON MICROSCOPE SYSTEM AND METHOD OF INSPECTING A SPECIMEN USING THE SAME	OKUDA, HIROHITO
11020265	7075677	150	12/27/2004	METHOD OF OBSERVING A SPECIMEN USING A	OKUDA, HIROHITO

				SCANNING ELECTRON MICROSCOPE	
11042021	7205555 ✓	150	01/24/2005	DEFECT INSPECTION APPARATUS AND DEFECT INSPECTION METHOD	OKUDA, HIROHITO
11248697	7170593 ✓	150	10/11/2005	METHOD OF REVIEWING DETECTED DEFECTS	OKUDA, HIROHITO
11478615	Not Issued	30	07/03/2006	Apparatus and method for electron beam inspection with projection electron microscopy	OKUDA, HIROHITO
11488734 ✓	Not Issued	30	07/19/2006	Method and apparatus for inspecting defects of circuit patterns	OKUDA, HIROHITO
11601723 ✓	Not Issued	30	11/20/2006	Method and apparatus for inspecting pattern defects and mirror electron projection Type or multi-beam scanning type electron beam apparatus	OKUDA, HIROHITO

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